

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 14603-028US1	Application No.
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Gerhard Fritz	
		Filing Date	Group Art Unit

(37 CFR §1.98(b))

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,377,037	04/23/2002	Gordon Burns et al			
	AB	6,373,415	04/16/2002	Eric King et al			
	AC	5,017,860	05/21/1991	Warren Germer et al			
	AD	2003/0042886	03/06/2003	Guljeet Gandhi			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL	692 28 850	10/07/99	Germany			Abstract	
	AM	35 14 371	10/23/86	Germany			Abstract	
	AN	27 08 075	08/24/78	Germany			Abstract	
	AO	26 30 959	01/12/78	Germany			Abstract	
	AP	62-162917	07/18/87	Abstracts of Japan				
	AQ	59-042460	03/09/84	Abstracts of Japan				
	AR	2 319 345	05/20/98	Great Britain				
	AS	0 534 583	04/07/99	EPO				
	AT	1 563 677	03/26/80	Great Britain				
	AU	1 575 148	09/17/80	Great Britain				

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
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Examiner Signature /Minh Tang/ (04/24/2008)	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /MT/

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Examiner Initial	Desig. ID	Document
	AV	Nagura, H. et al. "Correction Method for a Single Chip Power Meter" IMTC, 1994 May 10-12, pp 1313-1316, XP 01021767, ISBN 0-7803-1880-3
	AW	
	AX	
	AY	

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Substitute Disclosure Form (PTO-1449)

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